

Advanced Computer Vision Week 07

Oct. 14, 2022 Seokju Lee



Let's Learn SIFT Algorithm

Scale Invariant Feature Transform (SIFT)

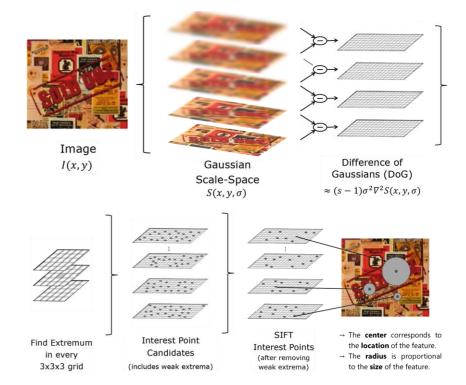
and its applications for image alignment and 2D object recognition.

Topics:

- (1) What is an Interest Point?
- (2) Detecting Blobs
- (3) SIFT Detector
- (4) SIFT Descriptor



Detected SIFT features with multiscale



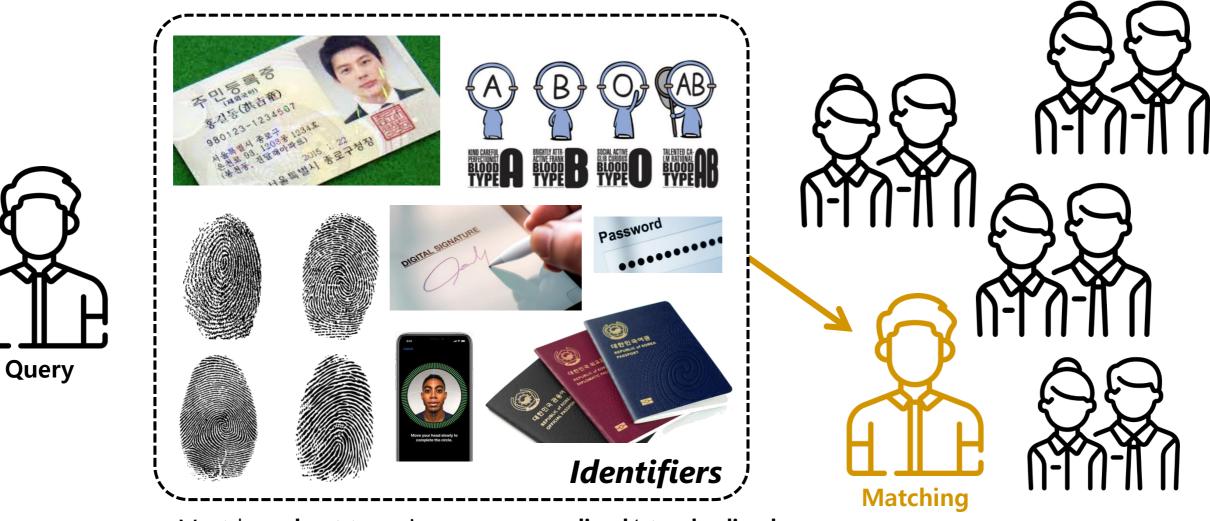
Parts of slides are by Prof. In So Kweon and Prof. Shree Nayar



SIFT Descriptor

What is Descriptor?

Descriptor = Set of **Distinctive** features and their **identifiers**



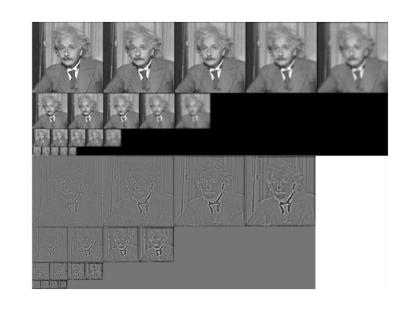
→ Must be **robust** to variances + **generalized/standardized**

SIFT: Scale Invariance

Scale space

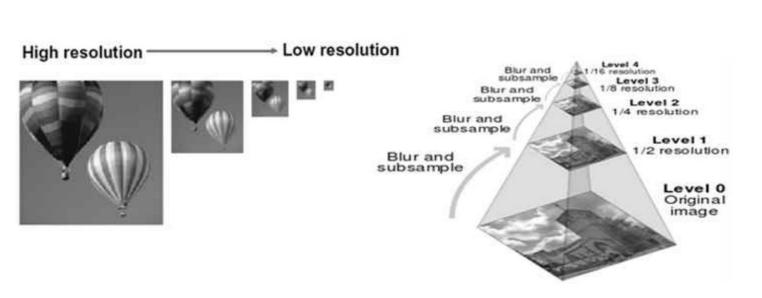
<u>Different scales</u> are necessary for describing different objects in the image, and we may not know the correct scale/size ahead of time (<u>generalization</u>).





Gaussian Pyramid

Image pyramid technique is used for reducing the memory usage and computational complexity.



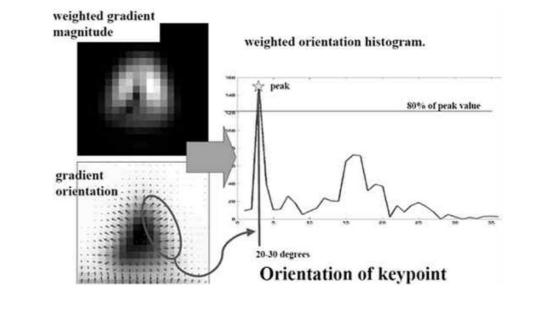
SIFT: Rotation Invariance

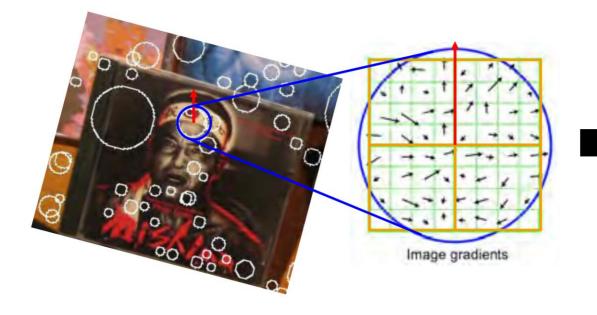
Compute gradient for each blurred image

$$m(x, y) = \sqrt{(L(x+1, y) - L(x-1, y))^2 + (L(x, y+1) - L(x, y-1))^2}$$

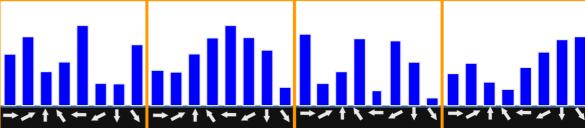
$$\theta(x,y) = \tan^{-1}((L(x,y+1)-L(x,y-1))/(L(x+1,y)-L(x-1,y)))$$

Histograms of gradient directions over spatial regions









- → **Normalized** histogram: invariant to **rotation**, **scale**, **brightness**
- → Can be directly used as a **signature** for matching SIFT Features!

Comparing SIFT Descriptors

Essentially comparing two arrays of data

Let $H_1(k)$ and $H_2(k)$ be two arrays of data of length N,

L2 Distance:

$$d(H_1, H_2) = \sqrt{\sum_{k} (H_1(k) - H_2(k))^2}$$

Smaller the distance metric, **better** the match.

Perfect match when $d(H_1, H_2) = 0$

Comparing SIFT Descriptors

Essentially comparing two arrays of data

Let $H_1(k)$ and $H_2(k)$ be two arrays of data of length N,

Normalized Correlation:

$$d(H_1, H_2) = \frac{\sum_k [(H_1(k) - \overline{H}_1)(H_2(k) - \overline{H}_2)]}{\sqrt{\sum_k (H_1(k) - \overline{H}_1)^2} \sqrt{\sum_k (H_2(k) - \overline{H}_2)^2}}$$

where:
$$\overline{H}_i = \frac{1}{N} \sum_{k=1}^{N} H_i(k)$$

Larger the distance metric, better the match.

Perfect match when $d(H_1, H_2) = 1$

*Correlation?



Source image

How do we **locate** the template in the image?





Template

Minimize:

$$E[i,j] = \sum_{m} \sum_{n} (f[i+m,j+n] - t[m,n])^{2}$$

$$E[i,j] = \sum_{m} \sum_{n} (f^{2}[i+m,j+n] + t^{2}[m,n] - 2f[i+m,j+n]t[m,n])$$

$$\rightarrow Maximize$$

*Correlation?



Source image

How do we **locate** the template in the image?





Template

Maximize:

$$R[i,j] = \sum_{m} \sum_{n} t[m,n] f[i+m,j+n] = t \otimes f$$

→ Cross-correlation

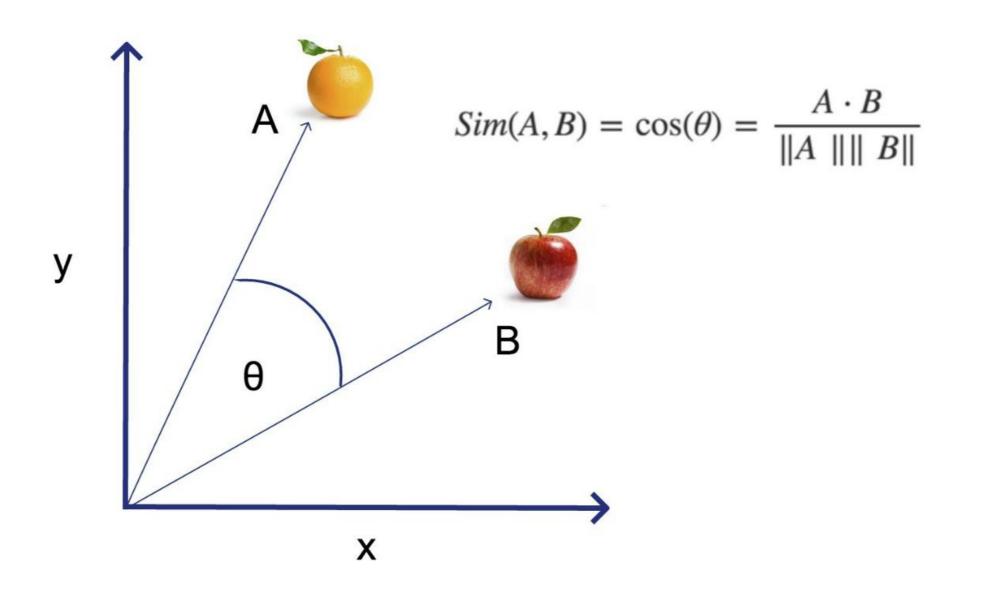
c.f.) convolution

$$\text{cosine similarity} = S_C(A,B) := \cos(\theta) = \frac{\mathbf{A} \cdot \mathbf{B}}{\|\mathbf{A}\| \|\mathbf{B}\|} = \frac{\sum\limits_{i=1}^n A_i B_i}{\sqrt{\sum\limits_{i=1}^n A_i^2} \sqrt{\sum\limits_{i=1}^n B_i^2}}$$



→ Result of cross-correlation

*Cosine Similarity



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Comparing SIFT Descriptors

Essentially comparing two arrays of data

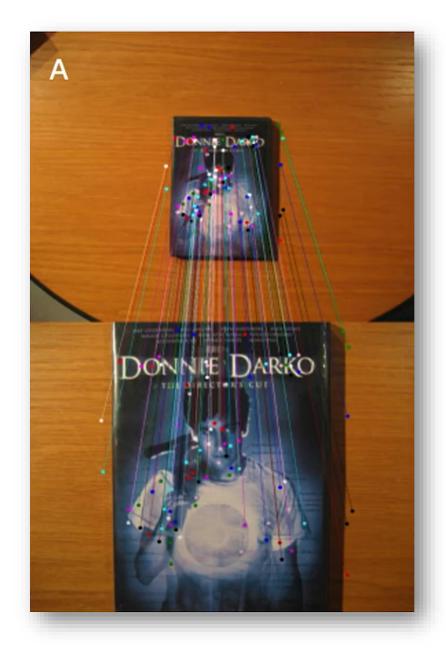
Let $H_1(k)$ and $H_2(k)$ be two arrays of data of length N,

Intersection:

$$d(H_1, H_2) = \sum_{k} \min(H_1(k), H_2(k))$$

Larger the distance metric, better the match.

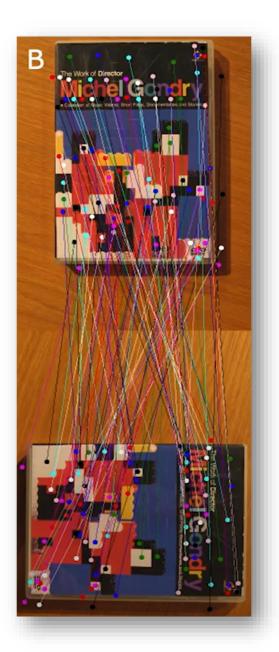
SIFT Results: Scale Invariance

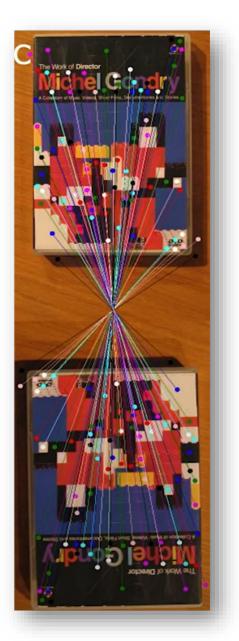




SIFT Results: Rotation Invariance







SIFT Results: Robust to Clutter







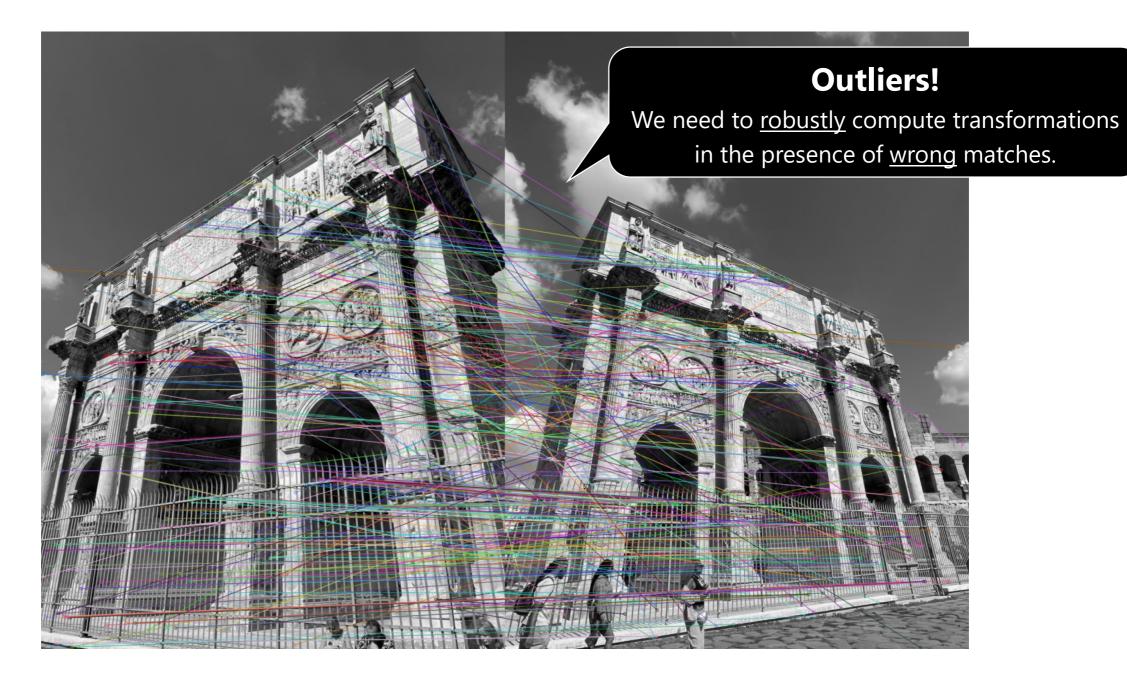
Experiment 1: SIFT Matching with Different Motions and Image Transformations

https://view.kentech.ac.kr/f088fa7f-874e-44bc-bd6d-6084b42dfdf7





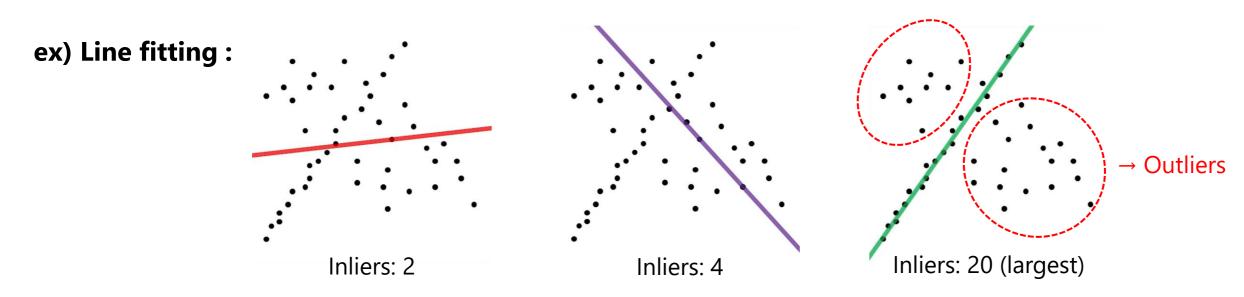
How to Handle Outliers?



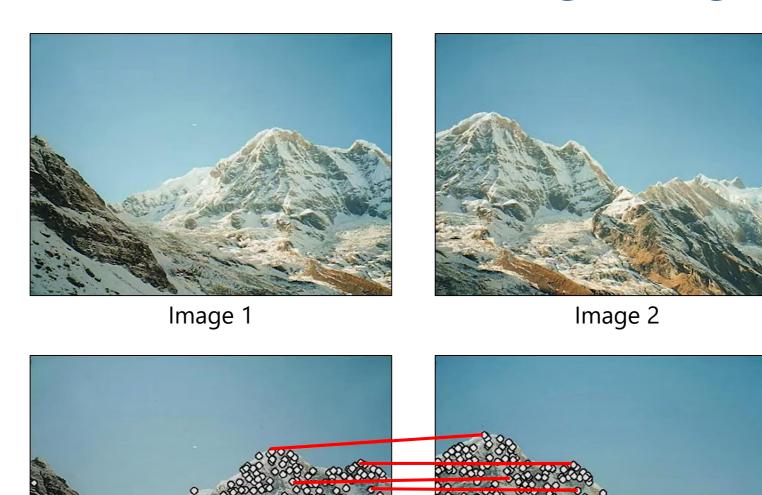
RANdom SAmple Consensus

General RANSAC Algorithm:

- 1. Randomly choose s samples. Typically s is the minimum samples to fit a model.
- Fit the model to the randomly chosen samples.
- 3. Count the number M of data points (inliers) that fit the model within a measure of error ε .
- 4. Repeat Steps 1-3 N times.
- 5. Choose the model that has the largest number M of inliers.



Experiment 2: Panorama Stitching using SIFT



Match SIFT interest points.

Experiment 2: Panorama Stitching using SIFT

Warp and combine images to create a larger image.

